

Welcome Message



Gordon Roberts
General Chair



Rob Aitken
Program Chair

It is our privilege to welcome you to the 44th IEEE International Test Conference (ITC) sponsored by the IEEE Computer Society and the Philadelphia Section. We are pleased to once again return to the Disneyland Resort Hotel in Anaheim, California - a great venue for ITC, the world's premier conference in test.

ITC Test Week 2013 is comprised of six full days of learning and networking opportunities. You will see and listen to various vendors and experts discuss electronics test technology for devices, boards and systems. Test week begins with a set of half-day tutorials extended over two days (Sunday and Monday). This format is new to ITC and is an excellent way to prepare for the regular technical program. In addition, this year ITC will feature three keynote addresses, with the first one given during the plenary session on Tuesday morning, followed by one each on Wednesday and Thursday. Timely topics important to the test industry will be showcased through the ITC lecture series and the advanced industrial practices (AIP) sessions. These sessions will provide an opportunity for attendees to learn the latest methods and techniques used by industry leaders in addressing some of today's most important test challenges.

The 2013 technical program will have 46 paper presentations covering various topic areas, five panel sessions and a poster session. Two days of specialized workshops are co-located with the conference on the last two days of Test Week test covering the hot topic of 3-D ICs and high-speed analog circuits. There will also be several open technical activities meetings held throughout the conference. These meetings include standards working groups as well as others.

We once again have a broad and diverse exhibitor floor comprised of EDA, hardware and test solutions providers covering almost any test need. The exhibitor floor is where you can see theory put into practice. Participating in demos and talking to the exhibitors is an integral part of the ITC experience, and one that lets you compare competing test solutions quickly and efficiently. The exhibit floor area will also be the site for the poster session as well as the Corporate Forum that will highlight new and exciting developments in test equipment, services, tools and methodologies. Returning in 2013 is the Exhibit Hall ITC Passport Program. Stamped passports can be turned in for an opportunity to win prizes.

On behalf of the International Test Conference 2013 steering committee, program committee and all the dedicated volunteers who are key to making the program complete, we welcome you to this year's exciting technical program and exhibits.